Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10511456	PAYNE, PATRICK
Examiner	Art Unit
Kim, Edward J	2109

	SEARCHED		
Class	Subclass	Date	Examiner
709	201-253		Edward J Kim
379	200-207		Edward J Kim
455	1-575.9		Edward J Kim

SEARCH NOTES				
Search Notes	Date	Examiner		
Also searched the Derwent, JPO, EPO, and IBM databases		Edward J Kim		
Also conducted inventor search on Patrick Payne		Edward J Kim		

	INTERFERENCE SEARCH			
Examiner	Date		Class	
_	Date		Class	

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